



## **iNEMI Meetings at OFC/NFOEC 2007 Conference**

**Monday, March 26, 2007**

**10:00 a.m. – 5:00 p.m. PDT**

**Anaheim Marriott – Orange County Ballroom 2 Room**

### **Fiber Connector End-Face Inspection Project and Optoelectronics TIG Meetings**

Meeting Location: Anaheim Marriott, Anaheim, CA, Los Angeles Room

#### **Meeting Overview**

The iNEMI Optoelectronics Technology Integration Group (TIG) has scheduled its iNEMI Roadmap gap analysis meeting plus an Fiber Connector End-Face Inspection Project meeting to coincide with the optical communications industry's OFC/NFOEC 2007 conference (March 25-29, Anaheim Convention Center, Anaheim, CA.); for conference information, go to: [www.ofcnfoec.org](http://www.ofcnfoec.org)

The one-day iNEMI meeting is scheduled for Monday, March 26, at the Anaheim Marriott, Los Angeles (adjacent to the Convention Center).

In addition, the Face-to-Face meeting scheduled at the Anaheim Marriott Hotel will have teleconference abilities, for those project participants who cannot attend in person.

Call-in Information: 1-888-231-5467 or 1-719-955-1389: Call Code: 113998

#### **Agenda**

10:00 – 10:15 am      Introductions and iNEMI Overview: David Godlewski, iNEMI

#### **(1) iNEMI Fiber Connector End-Face Inspection Project ( Phase I and Phase II):**

Project Chair: Tatiana Berdinskikh, Celestica

Project Co-Chair: Heather Tkalec, Alcatel, Canada

Project Focus: This project is developing requirements for allowable surface defects, such as scratches, pits, and contamination. Based on experimental data and the results of mathematical modeling, the group plans to define the zone criteria and pass/fail visual requirements for polished connectors, single mode and multimode fiber.

10:15 – 11:00 am      Phase I :Development of Cleanliness Specifications for Single-Mode Connectors with 2.5 and 1.25 mm Ferrules:  
Tatiana Berdinskikh, Celestica International Inc.  
Sun-Yuan Huang, Intel Corp., Douglas H. Wilson, PVI Systems Inc.

(2)11:00 – 11:30 am Application of occluded area in a production test environment  
Brian J. Roche, Cisco Systems, Douglas H. Wilson, PVI Systems Inc.

(3)11:30 – 12:00 noon MT Endface Quality Assessment for SM APC, Mike Hughes, USConect

12:00 noon – 1:00 pm Break

(4)1:00 – 1:30 pm Correlation Study: Endface Contamination and Insertion Loss on MM optical connectors, Steve Lytle, Westover Scientific

(5)1:30 – 2:00 pm VS receptacle, new glass type anti-reflection receptacle,  
Ryoji Nakamura, Toto USA

2:00- 2:30 pm The Effects of Static Field on Cleaning Fiber Optic Connections, Ed Forrest, ITW Chemtronics

2:30-3.00 Accumulation of Particles Near the Core during Repetitive Fiber Connector Matings and De-matings , Tatiana Berdinskikh, Celestica International Inc. , Sun-Yuan Huang, Intel Corp., Douglas H. Wilson, PVI Systems Inc.

### **iNEMI Optoelectronic TIG — Gap Analysis Meeting / Fiber Connector End-Face Inspection Project . Phase II**

Champion: Tatiana Berdinskikh, Celestica International Inc.

3:00 – 4:30 pm

Meeting Agenda:

- Statement of Work for Fiber Connector End-Face Inspection Project, Phase II
- Review the iNEMI Optoelectronics Technology Roadmap:  
David Godlewski, iNEMI  
Discuss industry needs and potential new projects to address those needs, open discussion,  
All

All meetings are open to anyone interested in attending.

#### **Additional information**

For additional information, please contact David Godlewski, iNEMI at [dgodlewski@inemi.org](mailto:dgodlewski@inemi.org) or review iNEMI's web site at [www.inemi.org](http://www.inemi.org)